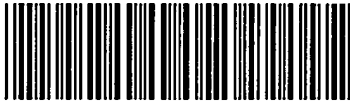


**Search Notes**

Application/Control No.

10/662,382

Examiner

Chris C. Chu

Applicant(s)/Patent under  
Reexamination

KANAI ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	781, 780, 777, 688 and 773	3/2/2005	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in USPAT; US-PGPUB; EPO; JPO; DERWENT; USOCR; and IBM_TDB;	3/2/2005	C.C.